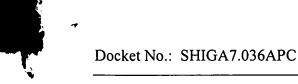
Customer No. 20,995



IAP20 RGG'G FGT/FTO 12 JAN 2006

INFORMATION DISCLOSURE STATEMENT

Applicant

Masuda et al.

App. No

Unknown

Filed

Herewith

For

POSITIVE PHOTORESIST

COMPOSITION AND METHOD OF

FORMING RESIST PATTERN

Examiner

Unknown

Art Unit

Unknown

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Enclosed for filing in the above-identified application is a PTO/SB/08 Equivalent listing 15 references to be considered by the Examiner. Also enclosed are 10 foreign patent references and/or non-patent literature as listed on the Information Disclosure Statement. Please note that JP 3-191351 corresponds to U.S. 5,290,657; JP 5-232697 corresponds to U.S. 5,424,167; JP 10-97066 corresponds to U.S. 6,210,855; and JP 11-204399 corresponds to U.S. 6,319,853.

This Information Disclosure Statement is being filed within three months of the filing date, and no fee is required.

The Commissioner is hereby authorized to charge any additional fees which may be required, or credit any overpayment, to Account No. 11-1410.

Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: 12 Jan. 2006

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PTO/SB/08 Equivalent

INFORMATION DISCLOSURE

Application No.	Unknown
Filing Date	Unknown Herewith 10/564510
First Named Inventor	Masuda, Yasuo
Art Unit	Unknown
Examiner	Unknown
Attorney Docket No.	SHIGA7.036APC

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STATEMENT BY APPLICANT	Art Unit	Unknown	
(Multiple sheets used when necessary)	Examiner	Unknown	
SHEET 1 OF 1	Attorney Docket No.	SHIGA7.036APC	
110 84	TENT DOCUMENTS	····	

U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
	1	5,290,657	03-01-1994	Uetani et al.	
	2	5,424,167	06-13-1995	Uetani et al.	
	3	6,210,855 B1	04-03-2001	Ueda et al.	
	4	6,319,853 B1	11-20-2001	Ishibashi et al.	
	5	6,187,500 B1	02-13-2001	Miyagi et al.	

	FOREIGN PATENT DOCUMENTS					
Examiner Initials	Cite No.	Foreign Patent Document Country Code-Number-Kind Code Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T ¹
	6	JP 3-191351	08-21-1991			
	7	JP 5-232697	09-10-1993			
	8	JP 2001-312052	11-09-2001	Tokyo Ohka Kogyo Co.		Abstract
	9	JP 2001-312059	11-09-2001	Tokyo Ohka Kogyo Co.		Abstract
	10	JP 2001-312060	11-09-2001	Tokyo Ohka Kogyo Co.		Abstract
	11	JP 2001-312066	11-09-2001	Tokyo Ohka Kogyo Co.		Abstract
	12	JP 10-97066	04-14-1998			
	13	JP 11-204399	07-30-1999			
	14	EP 0 677 789 A1	10-18-1995	Fuji Photo Film Co., Ltd.		
	15	EP 0 650 091 A1	04-26-1995	Sumitomo Chem. Co.		

		NON PATENT LITERATURE DOCUMENTS				
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ¹			

2277149:vr 011006

Examiner Signature

Date Considered

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

T¹ - Place a check mark in this area when an English language Translation is attached.